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FOR IMMEDIATE RELEASE

SMX PV Panel XRF Film Thickness and Composition Tools

HOLBROOK, New York - Solar Metrology, a global provider of X-Ray Fluorescence (XRF) analysis tools, introduces the SMX Tool Suite for XRF film thickness and composition measurement of CIS, CIGS, CIGSSe and CdTe photovoltaic depositions.

The SMX measurement system is a production-ready suite of XRF film thickness and composition measurement tools designed for research and process development, in-process monitoring and post-process quality control.

The SMX product line features four tool configurations: a Benchtop system, a Full-Panel Analysis system, an In-Line system and an In-Situ system. Utilizing a common XRF platform, adapted to optimal insertion points in the factory, allows for a consistent operator interface and insures reproducibility between SMX tools across the process.

Solar Metrology is a global leader in the development and manufacture of high-performance X-Ray Fluorescence (XRF) analysis tools, specifically engineered to meet the demanding thin film measurement requirements of the solar electric and renewable power industries.

To find out more, please visit **www.solarmetrology.com** or contact **info@solarmetrology.com**.